

FQB34P10TM_F085 100V P-Channel MOSFET

General Description

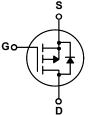
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

Features

- -33.5A, -100V, $R_{DS(on)} = 0.06\Omega @V_{GS} = -10 V$
- Low gate charge (typical 85 nC)
- Low Crss (typical 170 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating
- Qualified to AEC Q101
- RoHS Compliant





Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQB34P10TM_F085	Units
V _{DSS}	Drain-Source Voltage		-100	V
I _D	Drain Current - Continuous ($T_C = 25^{\circ}C$) - Continuous ($T_C = 100^{\circ}C$)		-33.5	А
			-23.5	А
I _{DM}	Drain Current - Pulsed	(Note 1)	-134	А
V _{GSS}	Gate-Source Voltage		± 25	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	2200	mJ
I _{AR}	Avalanche Current	(Note 1)	-33.5	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	15.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-6.0	V/ns
P _D	Power Dissipation $(T_A = 25^{\circ}C)^{*}$		3.75	W
	Power Dissipation $(T_C = 25^{\circ}C)$		155	W
	- Derate above 25°C		1.03	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

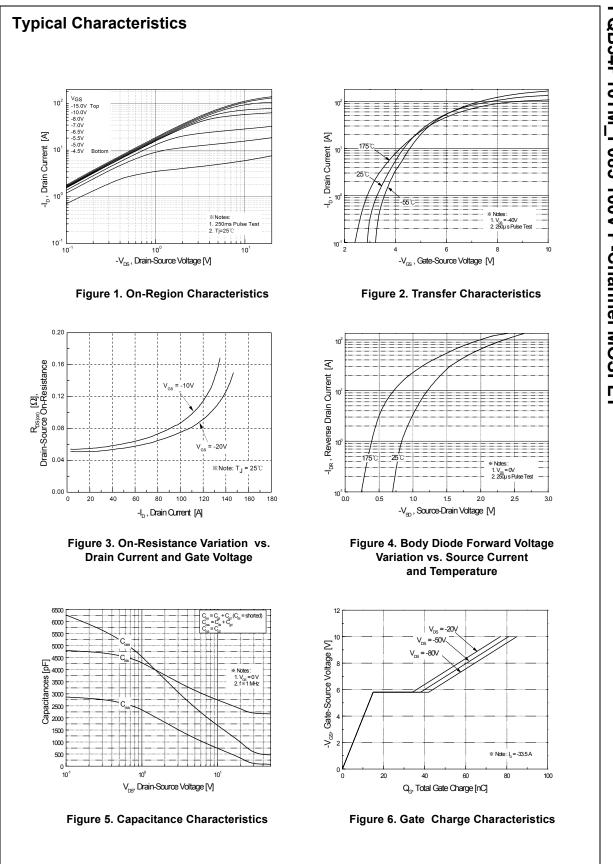
Symbol	Parameter	Тур	Max	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.97	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W	

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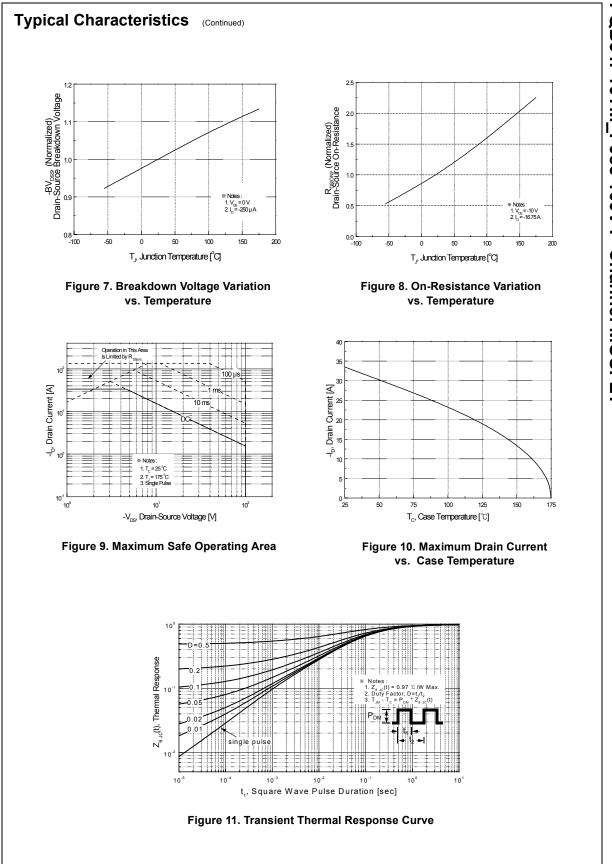
March 2016 QFET[™]

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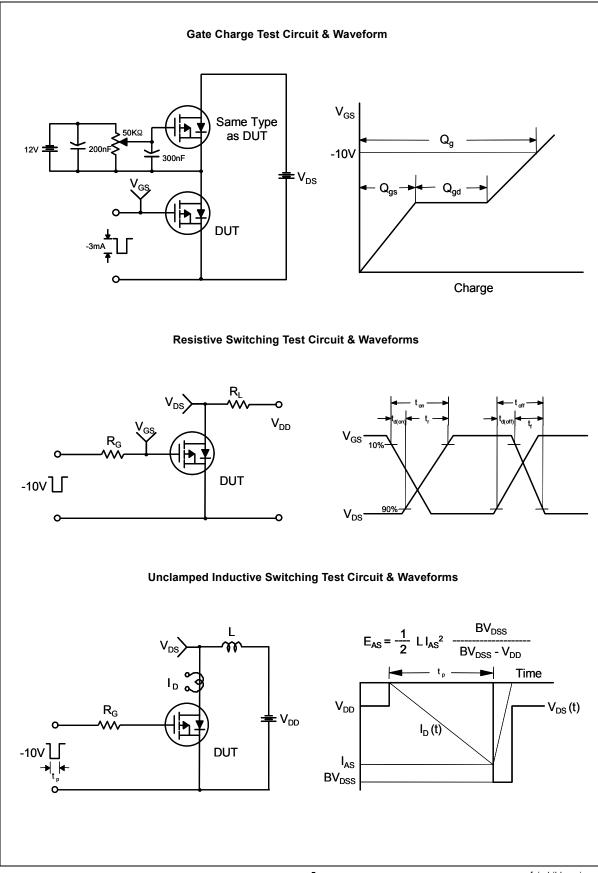
teristics ain-Source Breakdown Voltage eakdown Voltage Temperature efficient to Gate Voltage Drain Current te-Body Leakage Current, Forward te-Body Leakage Current, Reverse teristics te Threshold Voltage tic Drain-Source -Resistance	$\begin{split} V_{GS} &= 0 \ V, \ I_D = -250 \ \mu A \\ I_D &= -250 \ \mu A, \ Referenced \ to \ 25^\circ C \\ V_{DS} &= -100 \ V, \ V_{GS} &= 0 \ V \\ V_{DS} &= -80 \ V, \ T_C &= 150^\circ C \\ V_{GS} &= -25 \ V, \ V_{DS} &= 0 \ V \\ V_{GS} &= 25 \ V, \ V_{DS} &= 0 \ V \\ \end{split}$	-100 -2.0	 -0.1 	 -1 -10 -100 100	V V/°C μΑ μΑ nA
ain-Source Breakdown Voltage eakdown Voltage Temperature efficient to Gate Voltage Drain Current te-Body Leakage Current, Forward te-Body Leakage Current, Reverse teristics te Threshold Voltage tic Drain-Source	$I_{D} = -250 \ \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$ $V_{DS} = -100 \ \text{V}, \ V_{GS} = 0 \ \text{V}$ $V_{DS} = -80 \ \text{V}, \ T_{C} = 150^{\circ}\text{C}$ $V_{GS} = -25 \ \text{V}, \ V_{DS} = 0 \ \text{V}$ $V_{GS} = 25 \ \text{V}, \ V_{DS} = 0 \ \text{V}$		-0.1 	 -1 -10 -100	V/°C μA μA nA
eakdown Voltage Temperature efficient To Gate Voltage Drain Current te-Body Leakage Current, Forward te-Body Leakage Current, Reverse teristics te Threshold Voltage tic Drain-Source	$I_{D} = -250 \ \mu\text{A}, \text{ Referenced to } 25^{\circ}\text{C}$ $V_{DS} = -100 \ \text{V}, \ V_{GS} = 0 \ \text{V}$ $V_{DS} = -80 \ \text{V}, \ T_{C} = 150^{\circ}\text{C}$ $V_{GS} = -25 \ \text{V}, \ V_{DS} = 0 \ \text{V}$ $V_{GS} = 25 \ \text{V}, \ V_{DS} = 0 \ \text{V}$			-10 -100	μA μA nA
te-Body Leakage Current, Forward te-Body Leakage Current, Reverse teristics te Threshold Voltage tic Drain-Source	$V_{DS} = -80 \text{ V}, \text{ T}_{C} = 150^{\circ}\text{C}$ $V_{GS} = -25 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$ $V_{GS} = 25 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			-10 -100	μA nA
te-Body Leakage Current, Forward te-Body Leakage Current, Reverse teristics te Threshold Voltage tic Drain-Source	$V_{GS} = -25 V, V_{DS} = 0 V$ $V_{GS} = 25 V, V_{DS} = 0 V$			-100	nA
te-Body Leakage Current, Reverse teristics te Threshold Voltage tic Drain-Source	V _{GS} = 25 V, V _{DS} = 0 V				
teristics te Threshold Voltage tic Drain-Source				100	nA
te Threshold Voltage tic Drain-Source	$V_{DS} = V_{GS}, I_D = -250 \mu A$	-2 0			
te Threshold Voltage tic Drain-Source	V_{DS} = V_{GS} , I_D = -250 μ A	-2 0			
tic Drain-Source	D3 03, D - 1			-4.0	V
	1011 1011 10 1	-		-	
$V_{CS} = -10 V_{.1D} = -16.75 A$			0.049	0.06	Ω
ward Transconductance	V_{DS} = -40 V, I_{D} = -16.75 A (Note 4)		23		S
haraatariatioa					
land Operations			2240	2010	۳E
			-		pF pF
	f = 1.0 MHz				pr pF
n-On Delay Time	V _{DD} = -50 V, I _D = -33.5 A,		25	60	ns
n-On Rise Time	55 5		250	510	ns
n-Off Delay Time	(Note 4 E)		160	330	ns
	(NOLE 4, 5)		-		ns
al Gate Charge	V _{DS} = -80 V, I _D = -33.5 A,		85	110	nC
•	V _{GS} = -10 V				nC
te-Drain Charge	(Note 4, 5)		45		nC
ce Diode Characteristics a	nd Maximum Ratings				
	•			-33.5	А
ximum Pulsed Drain-Source Diode F	orward Current			-134	А
ximum Pulsed Drain-Source Diode F ain-Source Diode Forward Voltage	Forward Current V_{GS} = 0 V, I _S = -33.5 A			-134 -4.0	A V
			 160		
	n-On Rise Time n-Off Delay Time n-Off Fall Time al Gate Charge te-Source Charge te-Drain Charge	ut Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHztput Capacitancef = 1.0 MHz Characteristics $V_{DD} = -50 \text{ V}, I_D = -33.5 \text{ A},$ R_G = 25 Ω n-On Delay Time $V_{DD} = -50 \text{ V}, I_D = -33.5 \text{ A},$ R_G = 25 Ω n-Off Fall Time $(Note 4, 5)$ al Gate Charge $V_{DS} = -80 \text{ V}, I_D = -33.5 \text{ A},$ $V_{GS} = -10 \text{ V}$	ut Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHztput Capacitancef = 1.0 MHzCharacteristicsn-On Delay Time n-On Rise Time $V_{DD} = -50 \text{ V}, I_D = -33.5 \text{ A},$ $R_G = 25 \Omega$ n-Off Delay Time n-Off Fall Time al Gate Charge $V_{DS} = -80 \text{ V}, I_D = -33.5 \text{ A},$ $V_{GS} = -10 \text{ V}$ te-Drain Charge $V_{DS} = -80 \text{ V}, I_D = -33.5 \text{ A},$ $V_{GS} = -10 \text{ V}$ te-Drain Charge $V_{OS} = -10 \text{ V}$ te Diode Characteristics and Maximum Ratings	ut Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ 2240 tput Capacitance f = 1.0 MHz 730 verse Transfer Capacitance 170 Characteristics 25 m n-On Delay Time $V_{DD} = -50 \text{ V}, I_D = -33.5 \text{ A},$ 25 n-On Rise Time $V_{DD} = -50 \text{ V}, I_D = -33.5 \text{ A},$ 250 n-Off Delay Time $(Note 4, 5)$ 160 n-Off Fall Time $V_{DS} = -80 \text{ V}, I_D = -33.5 \text{ A},$ 85 te-Source Charge $V_{GS} = -10 \text{ V}$ 15 te-Drain Charge (Note 4, 5) 45	ut Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ 2240 2910 tput Capacitance f = 1.0 MHz 730 950 verse Transfer Capacitance r = 1.0 MHz 170 220 Characteristics n-On Delay Time $V_{DD} = -50 \text{ V}, I_D = -33.5 \text{ A},$ 25 60 n-On Rise Time $V_{DD} = -50 \text{ V}, I_D = -33.5 \text{ A},$ 250 510 n-Off Delay Time $R_G = 25 \Omega$ (Note 4, 5) 210 430 al Gate Charge $V_{DS} = -80 \text{ V}, I_D = -33.5 \text{ A},$ 85 110 te-Source Charge $V_{GS} = -10 \text{ V}$ 45 te-Drain Charge (Note 4, 5) 45



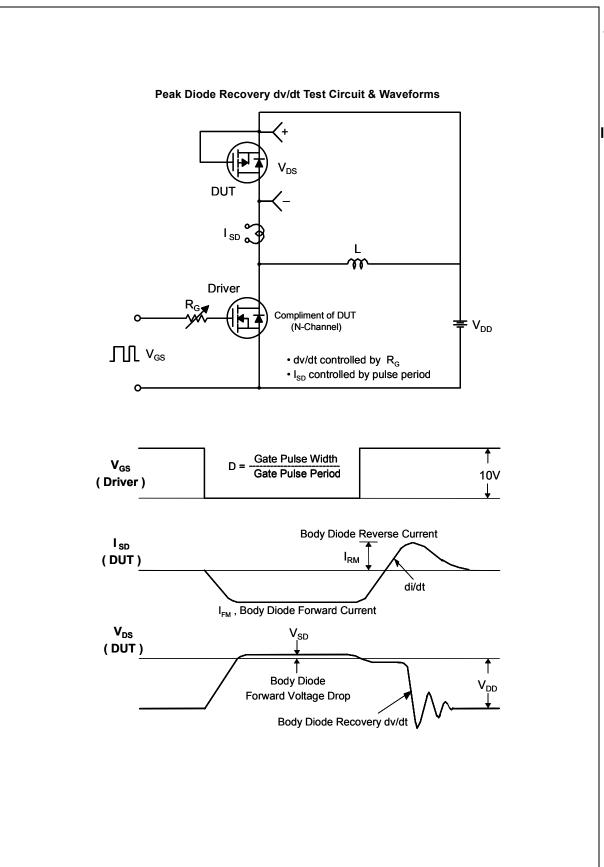
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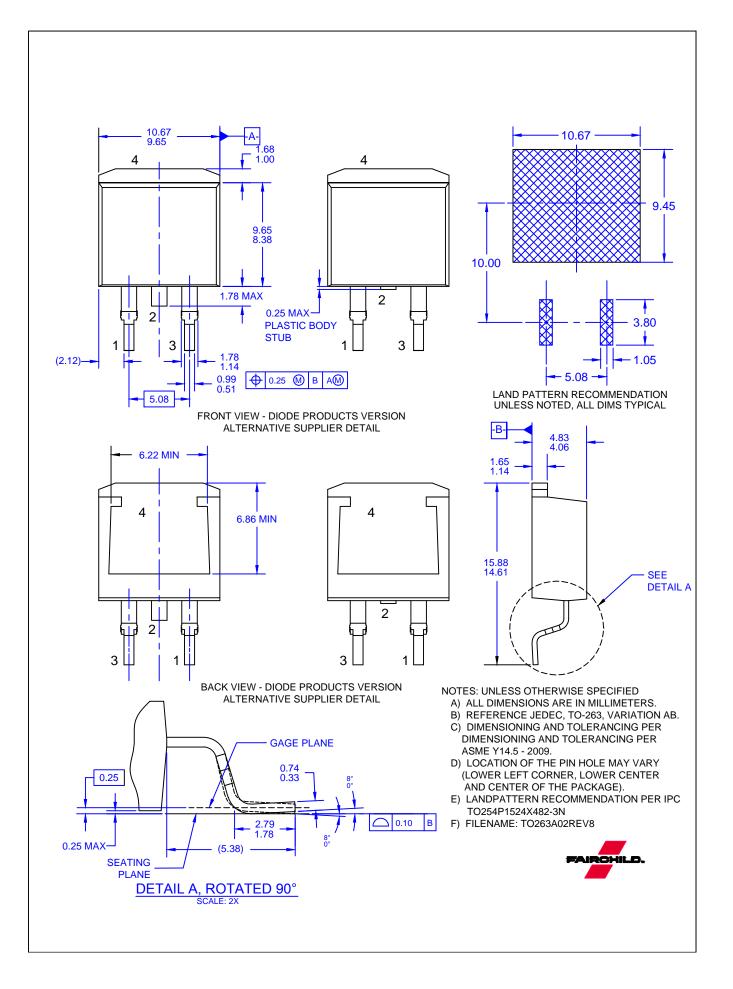
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